

(19) World Intellectual Property Organization  
International Bureau



(43) International Publication Date  
13 June 2002 (13.06.2002)

PCT

(10) International Publication Number  
**WO 02/47072 A1**

(51) International Patent Classification<sup>7</sup>: **G11B 7/0045**

(21) International Application Number: PCT/EP01/13735

(22) International Filing Date:  
23 November 2001 (23.11.2001)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:  
00204315.6 4 December 2000 (04.12.2000) EP

(71) Applicant: **KONINKLIJKE PHILIPS ELECTRONICS N.V.** [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).

(72) Inventor: **SPRUIT, Johannes, H., M.**; Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).

(74) Agent: **DEGUELLE, Wilhelmus, H., G.**; Internationaal Octrooibureau B.V., Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).

(81) Designated States (*national*): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NO, NZ, PH, PL, PT, RO, RU, SD, SE, SG, SI, SK, SL, TJ, TM, TR, TT, TZ, UA, UG, UZ, VN, YU, ZA, ZW.

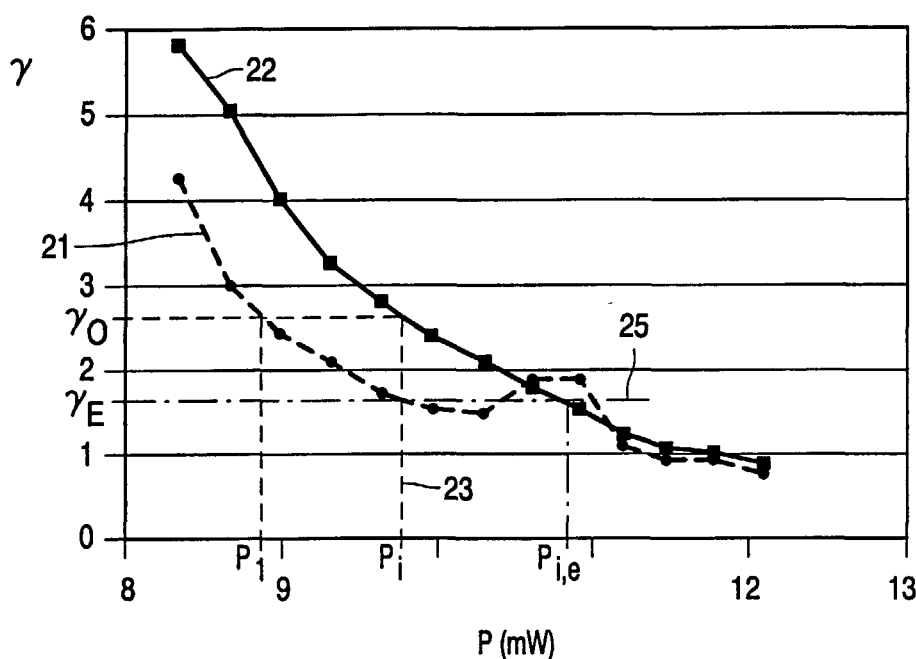
(84) Designated States (*regional*): ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

**Published:**

- with international search report
- before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments

[Continued on next page]

(54) Title: METHOD AND OPTICAL RECORDING APPARATUS FOR DETERMINING THE OPTIMUM WRITE POWER



(57) Abstract: A method and an optical recording apparatus for determining the optimum write power in an OPC-procedure are described. The method involves erasing a test area, recording test patterns in the test area, reading the recorded test patterns and determining the optimum write power from signal portions of the read signal. Erasing the test area, even when no signals are recorded therein, produces a reliable and unambiguous value of the optimum write power.



---

*For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.*